



SHEET 1 OF 1

INFORMATION DISCLOSURE  
CITATION IN AN  
APPLICATION

(PTO-1449)

ATTY. DOCKET NO.  
55071-129SERIAL NO.  
10/083,694APPLICANT  
Bruce W. SMITHFILING DATE  
February 27, 2002GROUP  
2851

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
PK		US 5,229,230	07/20/1993	Kamon	
PK		US 5,821,014	10/13/1998	Chen et al.	
PK		US 6,048,647	04/11/2000	Miyazaki et al.	
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						Yes	No
PK	A2	EP 1 174 784	01/23/2002	ASM LITHOGRAPHY B.V. and ASML MASKTOOLS NETHERLANDS B.V.			
PK	A1	EP 1 152 288	11/07/2001	ASML MASKTOOLS NETHERLANDS B.V.			
PK		JP 11143047 English abstract	05/28/1999	NEC Corp.			
PK		JP 08186073 English abstract	07/16/1996	MITSUBISHI ELECTRIC CORP.			
PK		JP 07064274 English abstract	03/10/1995	SONY CORP.			

## OTHER ART INCLUDING ART OF THIS DATE (Patent, Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
PK	11C-2-32L	"NAKAO S ET AL", "A Novel RET for Random Pattern Formation Utilizing Attenuating Non-Phase-Shift Assist Pattern", pp. 44, 45, 2000, Tokyo, Japan XP010513500

EXAMINER

DATE CONSIDERED

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered.  
Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

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	A2	EP 1 174 764	01/23/2002	ASM LITHOGRAPHY B.V. and ASML MASKTOOLS NETHERLANDS B.V.			
	A1	EP 1 152 288	11/07/2001	ASML MASKTOOLS NETHERLANDS B.V.			
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